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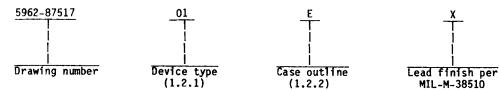
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1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function					
01	54LS590	8-bit binary counter with three-state output registers					

1.2.2 <u>Case outlines</u>. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	<u>Case outline</u>
Ε	D-2 (16-lead, .840" x .310" x .200"), dual-in-line package
F	F-5 (16-lead, .440" x .285" x .085"), flat
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings.

 $\overline{1/\text{ M}}$ ust withstand the added PD, due to short-circuit test, e.g., IOS.

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1.4 Recommended operating conditions.	· •		
Supply voltage range (V _{CC}) Minimum high level input voltage (V _{IL} Maximum low level input voltage (V _{IL} Maximum high level output current:	н) – – – -	- 2.0 V dc	
RCO		1 mA 1 mA	
Maximum low level output current: RCO		– 8 mA - 12 mA	
Counter clock frequency (f _{CCK}) Register clock frequency (f _{RCK})		 0 MHz to 20 MH 	
Minimum counter clock pulse width (t Minimum counter clear pulse width (t	WCCK)	- 25 ns - 20 ns	
Minimum register clock pulse width (Minimum setup time (t _{su}): CCKEN low before CCK+		- 20 ns - 20 ns	
CCLR inactive before CCK+ CCK before RCK+ 2/		- 20 ns - 40 ns	
Minimum hold time (T_h) Case operating temperature range (T_C))	- 0 ns 55°C to +125°	c
2. APPLICABLE DOCUMENTS			
2.1 Government specification and standa specification and standard, of the issue T Specifications and Standards specified in extent specified herein.	isted in t	hat issue of the De	partment of Defense Index of
SPECIFICATION			
MILITARY			
MIL-M-3dold - Microcircu	its, Gener	al Specification fo	r.
STANDARD			
MILITARY			•
MIL-STD-883 - Test Metho	ds and Pro	ocedures for Microel	ectronics.
(Copies of the specification and standar acquisition functions should be obtained f contracting activity.)	d required rom the co	l by manufacturers i ontracting activity	n connection with specific or as directed by the
2.2 Order of precedence. In the event references cited herein, the text of this	of a confl drawing sh	ict between the tex nall take precedence	t of this drawing and the
	will see case the	stable data from th register state will	ne counter outputs. The be one clock pulse behind
STANDARDIZED	SIZE A	:	59ő2-ช7ó17

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3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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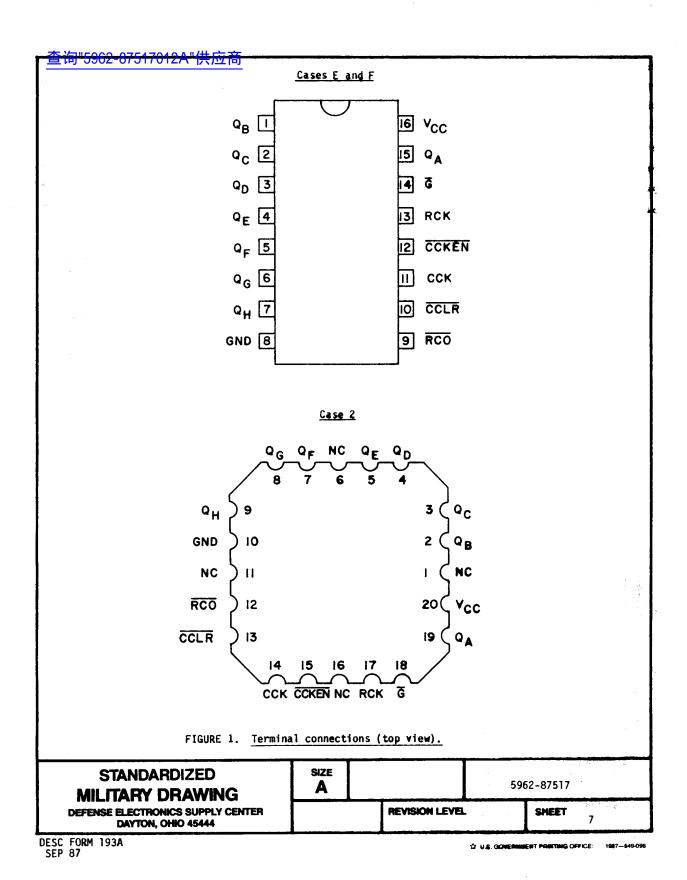
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Test	Symbol	-55°C < T(itions c < +125°C vise specified	 Group A subgroups	İ	mits Max	 Unit
High level output voltage	v _{OH}		i = −1 mA 2.0 V	1,2,3	2.4		V
Low level output voltage	V _{OL}	V _{CC} = 4.5 V; V _{IN} = 0.7 V	Ioi = 8 mA RCO output	1,2,3		0.4	V
	 	or 2.0 V	I _{OL} = 12 mA Q output	1,2,3		0.4	 V
Input clamp voltage	AIC	V _{CC} = 4.5 V; I _I	y = -18 mA	1,2,3		-1.5] V
High level input current	I _{IH1}	V _{CC} = 5.5 V; V _{IN}	ı = 7.0 V	1,2,3		0.1	l mA
	I IH2	$V_{CC} = 5.5 \text{ V; } V_{IN}$	ı = 2.7 V	1,2,3] 20 	μА
Low level input current	IIL	V _{CC} = 5.5 V; V _{IN} = 0.4 V	 CCK input 	1,2,3		 -0.8 	mA
	 	 	All other inputs	1,2,3		 -0.2 	mA
Short-circuit output current	Ios	 V _{CC} = 5.5 V; V _{OUT} = 0.0 V	 RCO output	1,2,3	-20	 -100 	mA
		1/	Q output	1,2,3	-30	-130	mA
Off-state output current, high level voltage applied	IOZH	 V _{CC} = 5.5 V; V _{OU} V _{IN} = 0.7 V or 2	T = 2.7 V	1,2,3	!	20	μΑ
Off-state output current, low level voltage applied	I _{OZL}	 V _{CC} = 5.5 V; V _{OU} V _{IN} = 0.7 V or 2	T = 0.4 V .0 V	1,2,3	:	-20	μА
See footnote at end of table.							
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_		1		Ţ	Lir	nits	Ţ
Test	Symbol	Condi -55°C < T _C unless otherw	< +125°C	Group A subgroups	 Min 	Max	Uni [.]
Supply current	Іссн	 V _{CC} = 5.5 V; All inputs grounded,	possible all outputs	1,2,3		 55 	l mA
	ICCL	lopen -		1,2,3	 	 65 	mA
	Iccz	1		1,2,3	 	65	l mA
Functional tests		 See 4.3.1c 		7]]		
Maximum count frequency	fMAX	$V_{CC} = 5.0 \text{ V}$ $ R_{L} = 666\Omega$	-	 9 	20		MH;
	<u> </u>	CL = 45 pF		10,11	12		MHz
Propagation delay time, CCK to RCO	t _{PLH1}	V _{CC} = 5.0 V		9		22	ns
CCK to RCO	tpHL1	RL = 1 kΩ CL = 30 pF		10,11	<u>'</u>	31 30	ns
	11752	See figure 4		10,11	<u> </u>	43	ns
Propagation delay time, CCLR to RCO	t _{PLH2}	 		9 10,11		45 64	ns ns
Propagation delay time, RCK to Q	t _{PLH3}	 V _{CC} = 5.0 V R _L = 667Ω		9 10,11		18 26	ns ns
·	tpHL3	CL = 45 pF See figure 4		9 10,11		33 47	ns ns
Propagation delay time, G to Q	tpZH	<u> </u> 		9 10,11		38	ns
2 00 Q	tpZL	1 		10,11		45 64	ns ns
Propagation delay time, G to Q	tpHZ	 V _{CC} = 5.0 V P _C = 6670		9 1		30	ns
5 60 Q	tp _{l 7}	KL = 6071 CL = 5 pF See figure 4	$RL = 667\Omega$ CL = 5 pF See figure 4			43 38 54	ns ns
1/ Not more than one output condition should not ex	ceed one so	e shorted at a timecond.	e and the durat	ion of the s	hort-c	ircuit	
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 	I	nputs			
Ğ	CCLR	CCKEN	I CCK	I I RCK I	 Device state
Н	X	X	ļ X	X	Disabled
ļL	L	х	ļ x	 	Clear
L	Н	H	l x	X	 No change
L	Н	L	I ↑	X	Internal count
I L	! н 	! L 	l ↑ 	! ↑ 	 External count

L = Low level voltage
H = High level voltage
X = Irrelevant
^ = Low to high clock transition.

FIGURE 2. Truth table.

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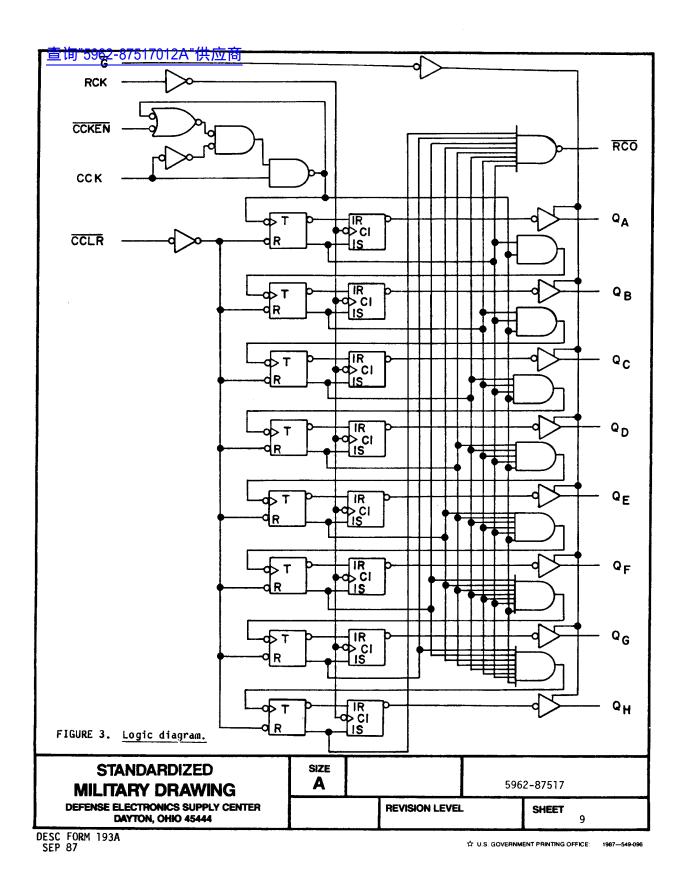
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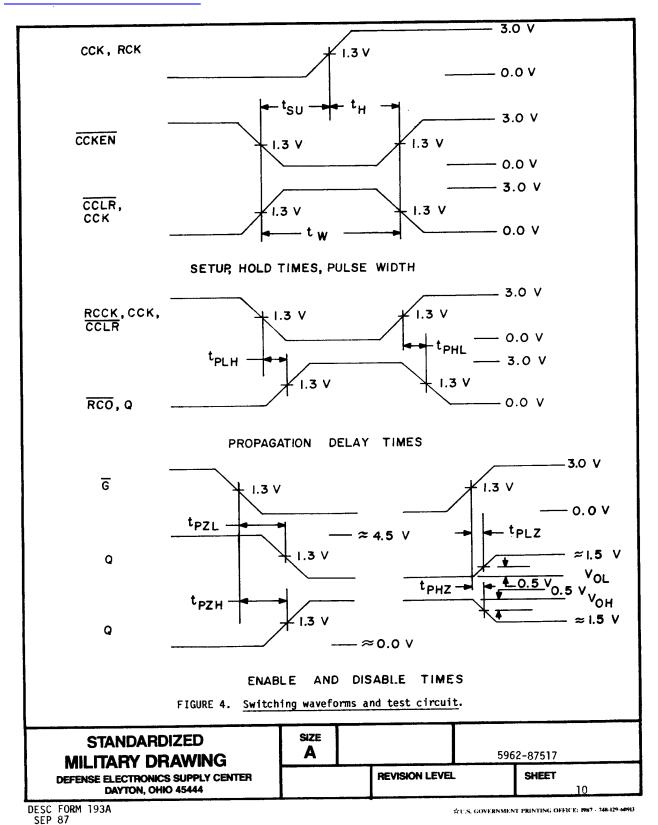
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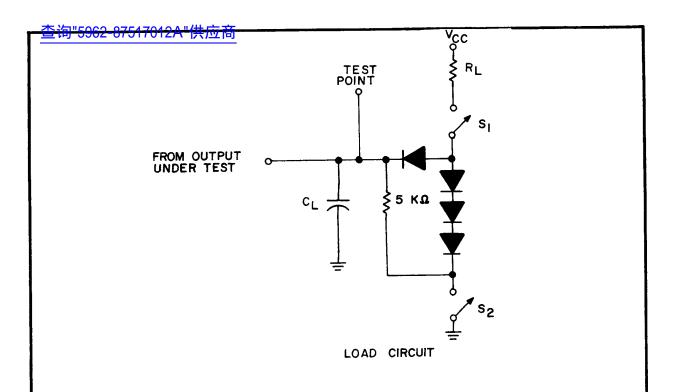
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NOTES:

- NUIES:

 1. The pulse generator shall have the following characteristics: PRR ≤ 1 MHz;

 t ≤ 15 ns; t ≤ 6 ns.

 2. CR includes scope probe, wiring, and stray capacitance without the package in the test fixture.

 3. All diodes are 1N3064, 1N916, or equivalent.
- 4. Switches S_1 and S_2 shall be set for enable and disable time tests as follows:

 t_{PZL} : S_1 closed, S_2 open

 t_{PZH} : S_1 open, S_2 closed

 $\rm t_{PLZ}$ and $\rm t_{PHZ}\colon\ S_1$ and $\rm S_2$ closed

FIGURE 4. Switching times and test circuit - Continued.

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- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 7 tests shall verify the truth table specified on figure 2 herein.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125$ °C, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

 MIL-STD-883 test requirements 	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 9, 10, 11**
Groups C and D end-point electrical parameters (method 5005)	1

*PDA applies to subgroup 1.
**Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

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- PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
 - 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.
- 6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/
5962-8751701EX	01295	SNJ54LS590J
5962-8751701FX	01295	SNJ54LS590W
5962-87517012X	01295	SNJ54LS590FK

<u>1/ Caution.</u> Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

01295

Vendor name and address

Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79701

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